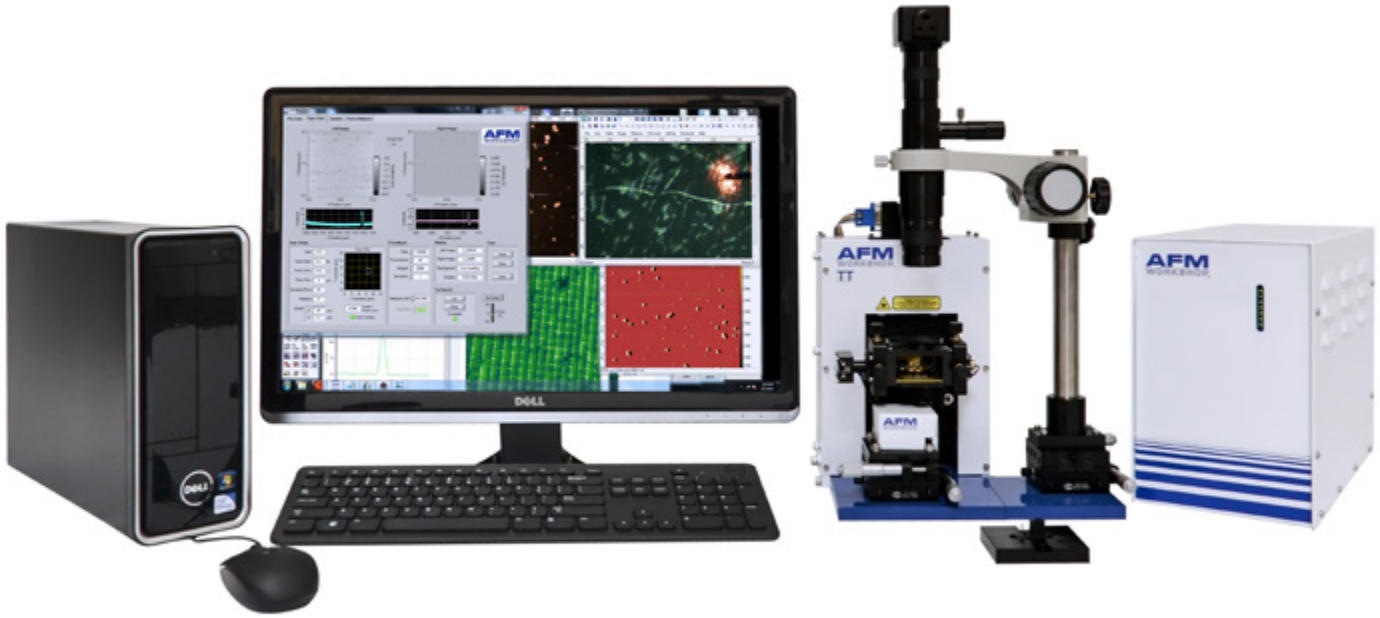
TT-AFM

This compact, tabletop Atomic Force Microscope has all the important features and benefits expected from a light lever AFM.

The TT-AFM includes everything you need for AFM scanning: a stage, control electronics, probes, manuals, and a video microscope.

For:

- **Nanotechnology Researchers**
  Wanting to do routine scanning of nano-structures.
- **Instrument Innovators**
  Using AFM as a platform to create a new instrument.
- **Educators**
  Teaching students about AFM construction, operation, and applications.



Sample Sizes	up to 1" X 1" X 1/4"
Standard Scanning Modes	Vibrating, Non Vibrating, Phase, LFM
Scanners	50 X 50 X 17 µ, 15 X 15 X 7 µ
Video Optical Microscope	Zoom to 400X, 2 µ resolution
Stage and Ebox Size	Compact Tabletop Design

STAGE

The TT-AFM stage has excellent thermal and mechanical stability required for high resolution AFM scanning. Additionally, its open design facilitates user modification.

Rigid Frame Design
The crossed beam design for the stage support is extremely rigid so the AFM is less susceptible to external vibrations.

Light Lever AFM Force Sensor
Light lever force sensors are used in almost all atomic force microscopes and permit many types of experiments.

Integrated Probe Holder/Probe Exchanger
A unique probe holder and clipping mechanism allows quick and easy probe exchange.

Direct Drive Z stage
A linear motion stage is used to move the probe in a perpendicular motion to the sample. Probe/sample angle alignment is not required, facilitating a much faster probe approach.

Small Footprint
The stage dimensions of 7.5 X 12" require little space and fit easily on a tabletop.

Precision XY Stage with Micrometer
The sample is moved relative to the probe with a precision XY micrometer stage. Thus, the sample can be moved without touching it.

Modes Electric Plug
A six pole electrical plug is located at the back of the stage to expand the capabilities of the TT-AFM.

XYZ Precision Piezo Scanner
The modified tripod design utilizes temperature compensated strain gauges which assure accurate measurements from images. Also, with this design it is possible to rapidly zoom into a feature visualized in an image.

Laser/Detector Alignment
Both the light lever laser and the photo detector adjustment mechanism may be directly viewed. This feature simplifies the laser/detector alignment.

Adaptable Sample Holder
At the top of the XYZ scanner is a removable cap that holds the sample. The cap can be modified - or a new cap can be designed – to hold many types of samples.

High resolution video microscope

Direct drive Z motor stage

Light lever force sensor

Mode input/output plug

XYZ linearized piezo scanner

XY sample translation stage

EBOX

Electronics in the TT-AFM are constructed around industry-standard USB data acquisition electronics. The critical functions, such as XY scanning, are optimized with a 24-bit digital to analog converter. With the analog Z feedback loop, the highest fidelity scanning is possible. Vibrating mode scanning is possible with both phase and amplitude feedback using the high sensitivity phase detection electronics.

24-bit scan DAC

Scanning waveforms for generating precision motion in the XY axis with the piezo scanners are created with 24-bit DACS driven by a 32-bit micro controller. With 24-bit scanning, the highest resolution AFM images may be measured. Feedback control using the XY strain gauges assures accurate tracking of the probe over the surface.

Phase and Amplitude Detector Circuit

Phase and amplitude in the Ebox are measured with highly stable phase and amplitude chips. The system can be configured to feed back on either phase or amplitude when scanning in vibrating mode.

Signal Accessible

At the rear of the Ebox is a 50 pin ribbon cable that gives access to all of the primary electronic signals without having to open the Ebox.

Status Lights

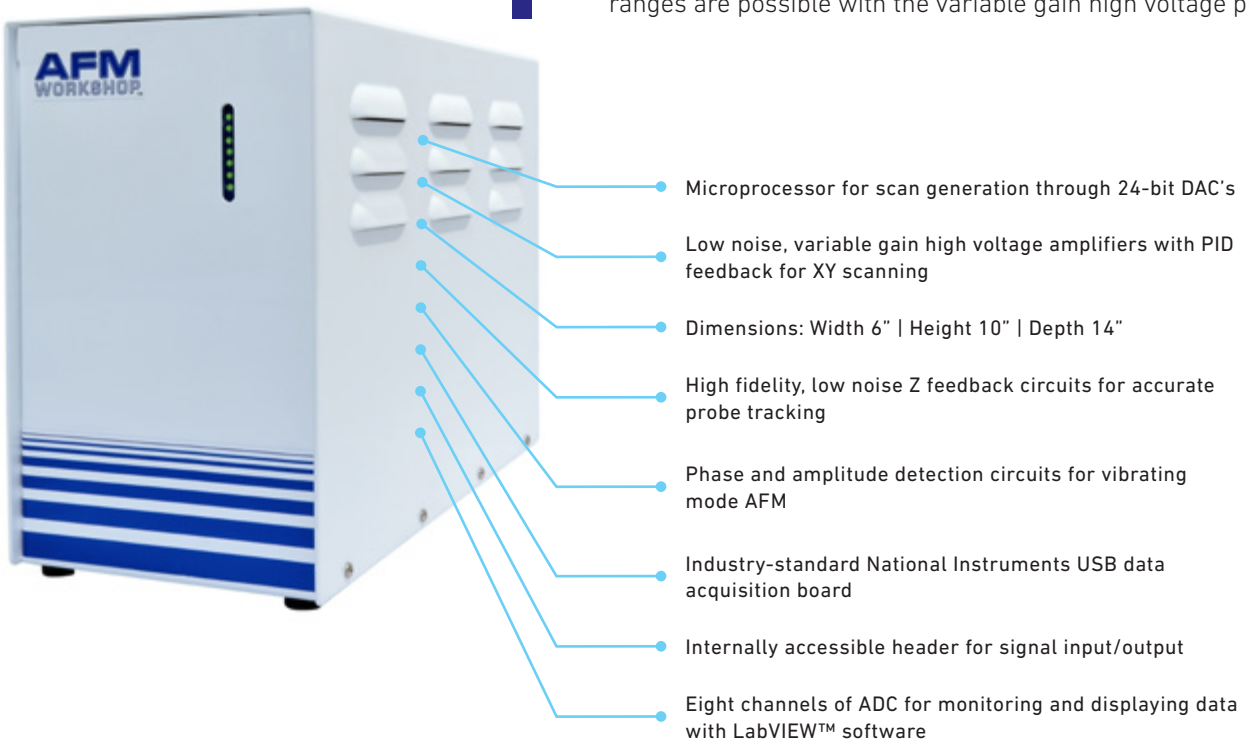
At the front of the Ebox is a light panel that has 7 lights. In the unlikely event of a circuit failure, these lights are used for determining the status of the Ebox power supplies.

Precision Analog Feedback

Feedback from the light lever force sensor to the Z piezoceramic is made using a precision analog feedback circuit. The position of the probe may be fixed in the vertical direction with a sample-and-hold circuit.

Variable Gain High Voltage Piezo Drivers

An improved signal to noise ratio, as well as extremely small scan ranges are possible with the variable gain high voltage piezo drivers.



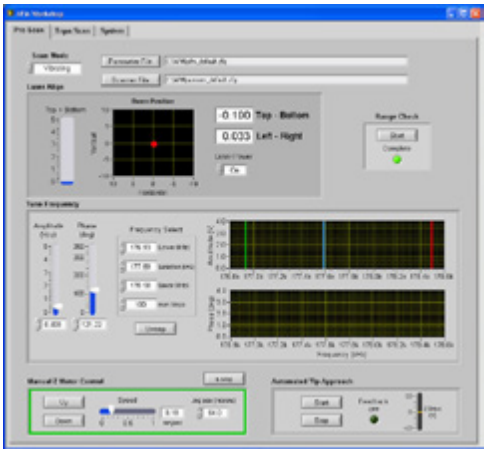
SOFTWARE

Software for acquiring images is designed with the industry-standard LabVIEW™ programming visual interface instrument design environment. There are many standard functions, including setting scanning parameters, probe approach, frequency tuning, and displaying images in real time.

LabVIEW™ facilitates rapid development for those users seeking to enhance the software with additional special features.

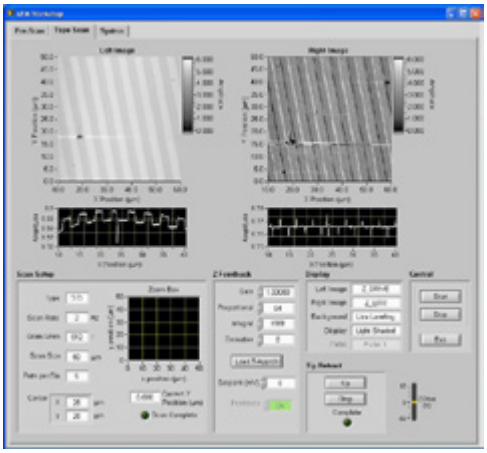
LabVIEW™ also enables the TT-AFM to be readily combined with any other instrument using LabVIEW™ VI.

Pre-scan Window



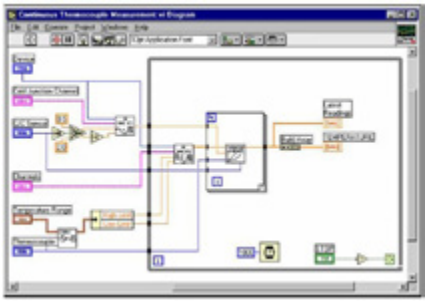
A pre-scan window includes all of the functions required before a scan is started. The functions are presented in a logical sequence on the screen.

Scan Window



Once all the steps in the pre-scan window are completed, the scan window is used for measuring images. Scan parameter, Z feedback parameters, and image view functions may be changed with dialogs on this screen.

LabVIEW™ Window



Industry-standard programming environment. Readily customized and modified for specialized applications. Instrumentation already using LabVIEW™ can be added to the TT-AFM to create new capabilities.

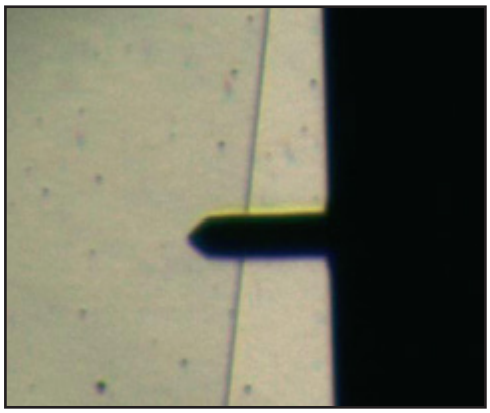
IMAGE ANALYSIS SOFTWARE

Included with the TT-AFM is the Gwyddion open source SPM image analysis software. This complete image analysis package has all the software functions necessary to process, analyze and display SPM images.

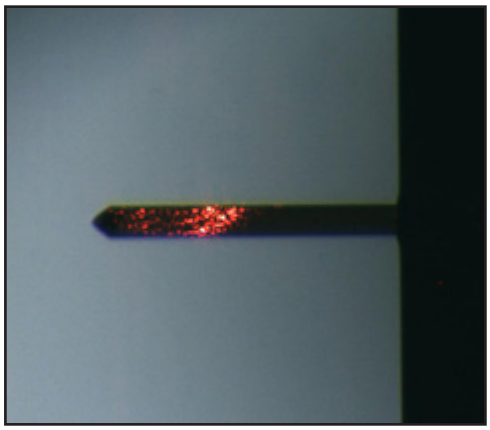
- Visualization: false color representation with different types of mapping
- Shaded, logarithmic, gradient- and edge-detected, local contrast representation, Canny lines
- OpenGL 3D data display: false color or material representation
- Easily editable color maps and OpenGL materials
- Basic operations: rotation, flipping, inversion, data arithmetic, crop, resampling
- Leveling: plane leveling, profiles leveling, three-point leveling, facet leveling, polynomial background removal, leveling along user-defined lines
- Value reading, distance and angle measurement
- Profiles: profile extraction, measuring distances in profile graph, profile export
- Filtering: mean, median, conservative denoise, Kuwahara, minimum, maximum, checker pattern removal
- General convolution filter with user-defined kernel
- Statistical functions: Ra, RMS, projected and surface area, inclination, histograms, 1D and 2D correlation functions, PSDF, 1D and 2D angular distributions, Minkowski functionals, facet orientation analysis
- Statistical quantities calculated from area under arbitrary mask
- Row/column statistical quantities plots
- ISO roughness parameter evaluation
- Grains: threshold marking and un-marking, watershed marking
- Grain statistics: overall and distributions of size, height, area, volume, boundary length, bounding dimensions
- Integral transforms: 2D FFT, 2D continuous wavelet transform (CWT), 2D discrete wavelet transform (DWT), wavelet anisotropy detection
- Fractal dimension analysis
- Data correction: spot remove, outlier marking, scar marking, several line correction methods (median, modus)
- Removal of data under arbitrary mask using Laplace or fractal interpolation
- Automatic XY plane rotation correction
- Arbitrary polynomial deformation on XY plane
- 1D and 2D FFT filtering
- Fast scan axis drift correction
- Mask editing: adding, removing or intersecting with rectangles and ellipses, inversion, extraction, expansion, shrinking
- Simple graph function fitting, critical dimension determination
- Force-distance curve fitting
- Axes scale calibration
- Merging and immersion of images
- Tip modeling, blind estimation, dilation and erosion

VIDEO MICROSCOPE

A video optical microscope in an Atomic Force Microscope serves three functions: aligning the laser onto the cantilever in the light lever AFM, locating surface features for scanning, and facilitating probe approach. The TT-AFM includes a high performance video optical microscope along with a 3 megapixel ccd camera, light source, microscope stand, and Windows software for displaying images.



Video microscope used to locate surface features for scanning. The vibrating mode cantilever is 125 µ long.

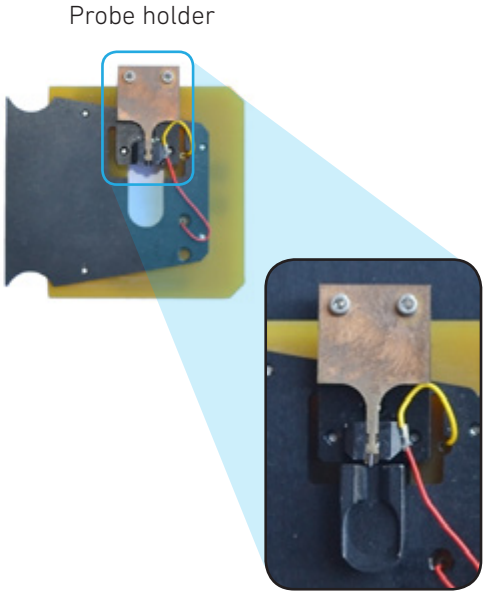


Laser alignment is greatly facilitated with the video optical microscope. This non-vibrating cantilever is 450 µ long. The red spot is from the laser reflecting off the cantilever.

PROBE HOLDER/ EXCHANGE

The TT-AFM utilizes a unique probe holder/exchange mechanism. Probes are held in place with a pring device that mates with a probe exchange tool. With the probe exchange tool, changing probes takes only a few minutes.

Probe exchange tool



Probe inserted in clip

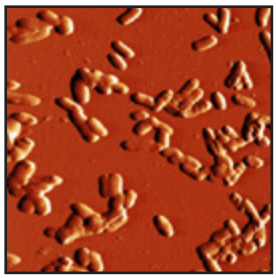
TT-AFM IMAGES

With a vertical noise floor of 0.1 nm and a horizontal resolution of 2 nm, most types of samples may be imaged with the TT-AFM.

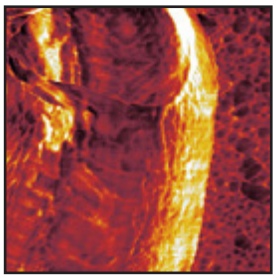
These include hard as well as soft samples.

OPEN DESIGN

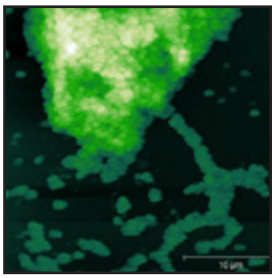
An open design is at the core of all products offered by the AFM Workshop. New types of experiments are more readily designed and implemented through the use of LabVIEW™ software. All the mechanical drawings for the TT-AFM are available in the documentation package option. Finally, the company's website offers a Users Forum to directly share specialized designs developed for the TT-AFM. For specialized applications, other types of scanners such as flexure and tubes can be easily added to the microscope stage.



40 x 40 µ - bacteria

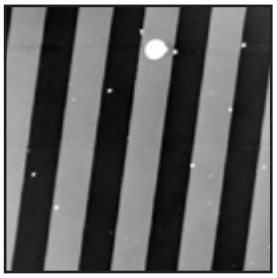


3 x 3 µ – phase image

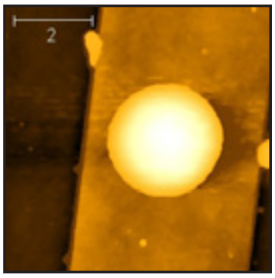


30 x 30 µ spores

MEMS multiple level gear

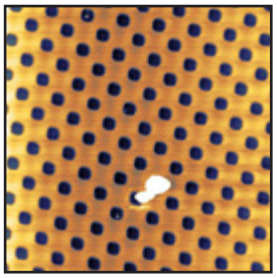


40 x 40 µ – test pattern

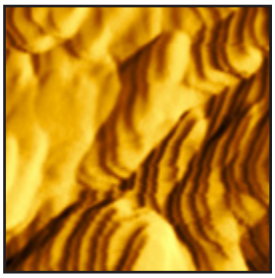


7 x 7 µ - defect

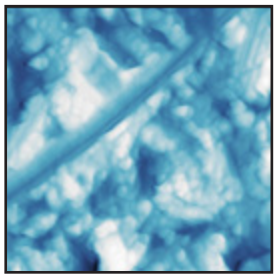
2 x 2 µ - si atomic terrace



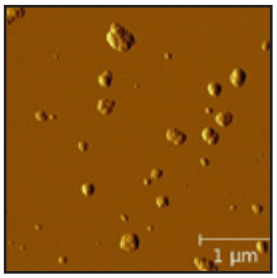
test pattern with defect



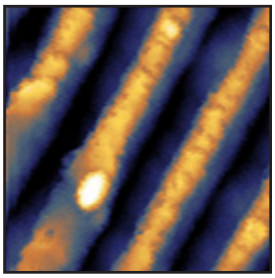
5 x 5 µ - terraces



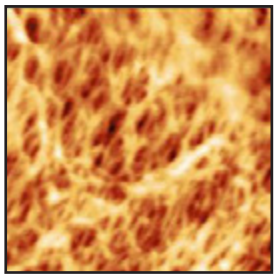
10 x 10 µ - scratch in metal



4 x 4 µ - 17 nm nanoparticles

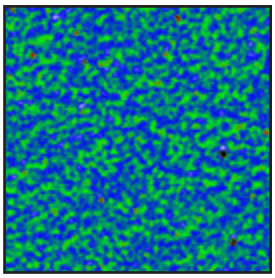


1 x 1 µ - 278 nm test pattern



2 x 2 µ - BOPP polymer fiber

25 x 25 µ - parasites



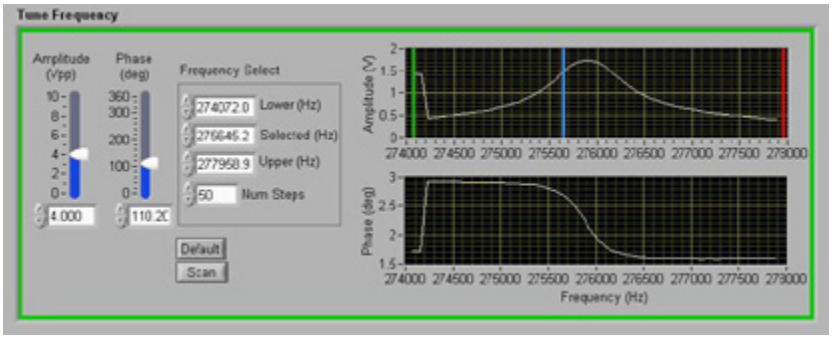
300 x 300 nm -phase PMMA

SCANNING MODES

Standard with every TT-AFM are nonvibrating (NV) mode and vibrating (V) modes for making topography scans.

Additional modes included with the product are lateral force imaging as well as phase mode imaging. All of the scanning modes that can be implemented with a light lever AFM are possible with the TT-AFM.

With the window below, the resonance frequency of a cantilever is readily measured. Additionally, the phase characteristics of the probe sample interaction are captured.

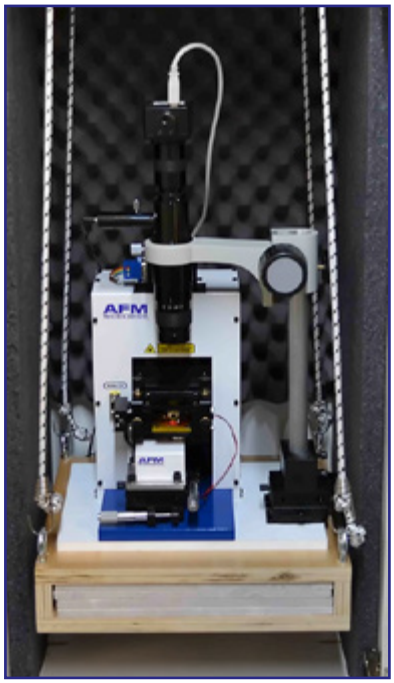


TT-AFM OPTIONS

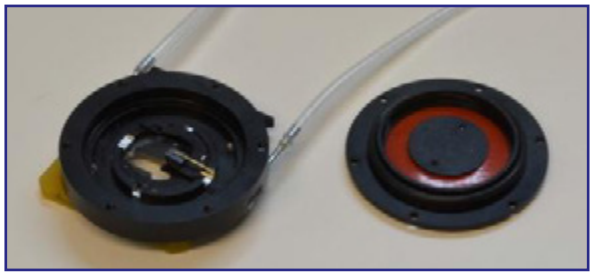
Although the TT-AFM comes with everything you need to make AFM images, several options are currently available.

- **Environmental Cell**
  Permits scanning in inert environments or liquids.
- **Scanner Fabrication Tool**
  Facilitates scanner fabrication.
- **High Resolution Scanner**
  Allows a range of 15 x 15 microns in XY and 7 µ in Z.
- **Vibration Cabinet**
  Reduces unwanted acoustic and structural vibrations.
- **Conductive AFM**
  Measures the 2D conductivity of sample surfaces.

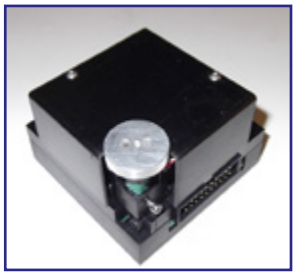
AFM Workshop regularly develops new Options.
Contact AFM Workshop for more information on options for the TT-AFM.



Vibration cabinet



Environmental cell



15 µ scanner

SPECIFICATIONS

50 Micron XYz Scanner

Type	Modified tripod
XY Linearity	< 1%
XY Range	> 50 µ
XY resolution	< 10 nm closed loop < 1 nm open loop
XY Actuator type	Piezo
Sensor type	Strain Gauge
Z Range	> 16 µ
Z Linearity	< 5 %
Z sensor noise	< 5 nm
Z feedback noise	< 0.2 nm*
Z Actuator Type	Piezo
Z Sensor type	Strain Gauge

15 Micron XYz Scanner

Type	Modified tripod
XY Linearity	< 1%
XY Range	> 15 µ
XY resolution	< 3 nm closed loop < 0.3 nm open loop
XY Actuator type	Piezo
Sensor type	Strain Gauge
Z Range	> 7 µ
Z Linearity	< 5 %
Z sensor noise	< 5 nm
Z feedback noise	< 0.1 nm*
Z Actuator Type	Piezo
Z Sensor type	None

Sample Holder

Type	Magnet
Max Lateral Dimensions	1"
Max. Height	0.25"

Light Lever AFM Force Sensor

Probe Types	Industry-standard
Probe insertion	Manual – probe exchange tool
Probe holding mechanism	Clip Vibrating mode piezo Electrical connector to probe
Laser/Detector adjustment range	+/- 1.5 mm
Adjustment resolution	1 µ
Minimum Probe to Objective	25 mm
Laser Type	670 nm diode, < 5 mw
Detector	
Type	4 quadrant
Band Width	> 500 kHz
Signals Transmitted	TL, BL, TR, BR
Gain	Lo, High Settings
Probe sample angle	10°

XY Translator

Range	25.4 mm
Resolution	2 µ
Type	Bearing - spring loaded
Lock Down	Yes

Z Motion

Type	Direct Drive
Range	25 mm
Drive Type	Stepper Motor
Min. Step Size	330 nm
Slew Rate	8 mm/minute
Limit Switch Top, Bottom	
Control	Software – rate, step size

Digital Data Input Output

Connection	USB
Scanning DAC	
Number	2
Bits	24
Frequency	7 kHz
Control DAC	
Number	2
Bits	14
Frequency	2 kHz
ADC	
Number	8
Bits	14
Frequency	48 kHz

Analog Electronics

Vibrating Mode	
Freq Range	2 kHz – 800 kHz
Output Voltage	10 Vpp
Demod. Freq	TBD
Z Feedback	
Type	PID
Bandwidth	> 3 kHz
Sample Hold	Yes
Voltage	0-150 V
XY Scan	
Voltage	0 – 150 V
Bandwidth	> 200 Hz
Pan & Zoom	22 Bits
Tip Approach Cutoff	> 20 µ sec.

SPECIFICATIONS *CONTINUED...*

Software

» Environment	LabVIEW™
» Operating System	Windows
» Image Acquisition	Real Time Display (2 of 8 channels)
» Control Parameters	
PID	Yes
Setpoint	Yes
Range	Yes
Scan Rate	Yes
Image Rotate	0 and 90°
» Laser Align	Yes
» Vibrating Freq. Display	Yes
» Force Distance	Yes
» Tip Approach	Yes
» Oscilloscope	Yes
» Image Store Format	Industry-standard
» Image Pixels	16 x 16 to 1024 x 1024
» H.V. Gain Control	XY and Z
» Real time display	Line Level, Light Shaded, Grey Color Pallet
» Calibration	System Window
» Probe Center	Yes

Video Microscope

	Minimum Zoom	Maximum Zoom
Field of view	2 X 2 mm	300 X 300 u
Resolution	20 µ	2 µ
Working Distance	114 mm	114 mm
Magnification	45 X	400 X

Computer

- » Industry-Standard Computer & Monitor (laptop available upon request)
- » Windows
- » AFMWorkshop LabVIEW.exe installed

* *Z Noise performance depends greatly on the environment the TT-AFM is used in. Best Z noise performance is obtained in a vibration free environment.*

** *Every effort is made to present accurate specifications, however, due to circumstances out of the AFMWorkshop's control specifications are subject to change.*